

FDD8796/FDU8796 N-Channel PowerTrench[®] MOSFET 25V, 35A, 5.7m Ω



General Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low $r_{\text{DS}(\text{on})}$ and fast switching speed.

Features

- Max $r_{DS(on)} = 5.7 \text{m}\Omega$ at $V_{GS} = 10 \text{V}$, $I_D = 35 \text{A}$
- Max $r_{DS(on)} = 8.0 \text{m}\Omega$ at $V_{GS} = 4.5 \text{V}$, $I_D = 35 \text{A}$
- Low gate charge: $Q_{g(10)} = 37nC(Typ)$, $V_{GS} = 10V$
- Low gate resistance
- Avalanche rated and 100% tested
- RoHS Compliant

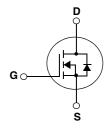
Application

- Vcore DC-DC for Desktop Computers and Servers
- VRM for Intermediate Bus Architecture









MOSFET Maximum Ratings T_C= 25°C unless otherwise noted

Symbol	Parameter	Ratings	Units	
V_{DS}	Drain to Source Voltage		25	V
V_{GS}	Gate to Source Voltage	±20	V	
	Drain Current -Continuous (Package Limited)		35	
I _D	-Continuous (Die Limited)		98	Α
	-Pulsed	(Note 1)	305	
E _{AS}	Single Pulse Avalanche Energy	(Note 2)	91	mJ
P_{D}	Power Dissipation		88	W
T _J , T _{STG}	Operating and Storage Temperature		-55 to 175	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case TO_252, TO_251	1.7	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient TO_252, TO_251	100	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient TO-252,1in ² copper pad area	52	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD8796	FDD8796	TO-252AA	13"	12mm	2500 units
FDU8796	FDU8796	TO-251AA	N/A (Tube)	N/A	75 units
FDU8796	FDU8796_F071	TO-251AA	N/A (Tube)	N/A	75 units

Symbol	Parameter	Test Conditions		Min	Тур	Max	Units
Off Chara	cteristics						
B _{VDSS}	Drain to Source Breakdown Voltage	I _D = 250μA, V _G	_S = 0V	25			V
ΔB _{VDSS} ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250μA, referenced to 25°C			7		mV/°C
DSS	Zero Gate Voltage Drain Current	$V_{DS} = 20V$ $V_{GS} = 0V$ $T_{J} = 150^{\circ}C$				1 250	μА
GSS	Gate to Source Leakage Current	V _{GS} = ±20V	-			±100	nA
n Chara	cteristics				1		
GS(th)	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D}$	= 250μA	1.2	1.8	2.5	V
ΔV _{GS(th)} ΔT _J	Gate to Source Threshold Voltage Temperature Coefficient	I _D = 250μA, referenced to 25°C			-6.7		mV/°C
•		V _{GS} = 10V, I _D = 35A			4.5	5.7	mΩ
56 ()	Drain to Source On Resistance	V_{GS} = 4.5V, I_D		6.0	8.0		
DS(on)	Drain to Gource Off Resistance	$V_{DS} = 10V, I_D = 35A$ $T_J = 175^{\circ}C$			6.9	9.5	
ynamic	Characteristics						
iss	Input Capacitance	V _{DS} = 13V, V _{GS} = 0V, f = 1MHz			1960	2610	pF
oss	Output Capacitance				455	605	pF
rss	Reverse Transfer Capacitance				315	475	pF
₹ _G	Gate Resistance	f = 1MHz			1.1		Ω
witching	g Characteristics						
d(on)	Turn-On Delay Time	V_{DD} =13V, I_{D} = 35A V_{GS} = 10V, R_{GS} = 20 Ω			10	20	ns
	Rise Time				24	39	ns
d(off)	Turn-Off Delay Time				99	158	ns
	Fall Time				57	91	ns
Q_{g}	Total Gate Charge	V _{GS} = 0 to10V			37	52	nC
\mathcal{Q}_{q}	Total Gate Charge	V _{GS} = 0 to 5V	V _{DD} =13V,		19	27	nC
Q_{gs}	Gate to Source Gate Charge	$V_{GS} = 0 \text{ to } 10V$ $V_{GS} = 0 \text{ to } 5V$ $I_{D} = 13V,$ $I_{D} = 35A,$ $I_{g} = 1.0\text{mA}$			6		nC
Q_{gd}	Gate to Drain Charge				6		nC
rain-Sou	rce Diode Characteristics						
V _{SD}	Oneman to Dunin Die de Welfere	$V_{GS} = 0V, I_S = 35A$			0.9	1.25	V
	Source to Drain Diode Voltage	$V_{GS} = 0V, I_S = 15A$			0.8	1.0	V
rr	Reverse Recovery Time	$I_F = 35A$, di/dt = $100A/\mu s$			30	45	ns
Q _{rr}	Reverse Recovery Charge	$I_F = 35A$, di/dt = $100A/\mu s$			23	35	nC

^{1:} Pulse time < $300\mu s$, Duty cycle = 2%. 2: Starting T_J = $25^{\circ}C$, L = 0.3mH, I_{AS} = 24.7A, V_{DD} = 23V, V_{GS} = 10V.



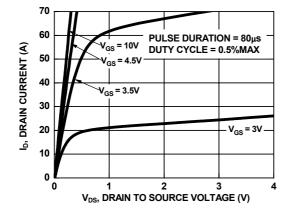


Figure 1. On Region Characteristics

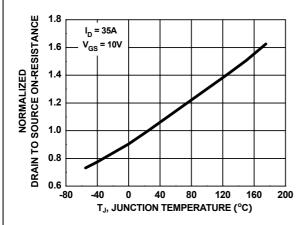


Figure 3. Normalized On Resistance vs Junction Temperature

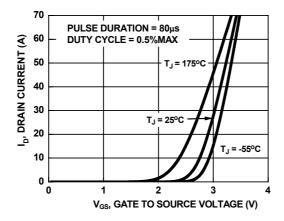


Figure 5. Transfer Characteristics

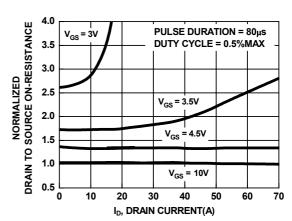


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

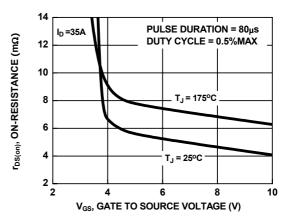


Figure 4. On-Resistance vs Gate to Source Voltage

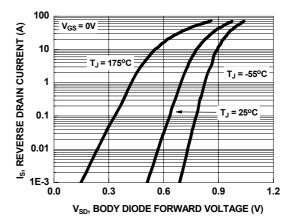
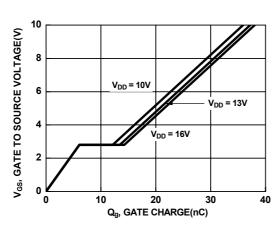


Figure 6. Source to Drain Diode Forward Voltage vs Source Current



Typical Characteristics T_J = 25°C unless otherwise noted

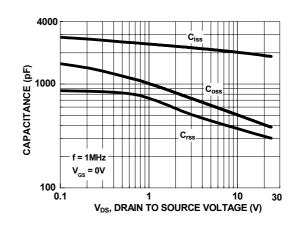
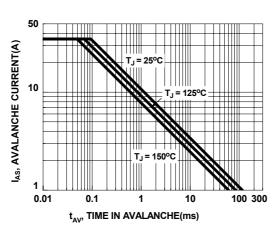


Figure 7. Gate Charge Characteristics

Figure 8. Capacitance vs Drain to Source Voltage



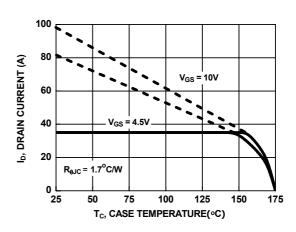
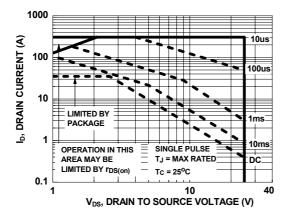


Figure 9. Unclamped Inductive Switching Capability

Figure 10. Maximum Continuous Drain Current vs Case Temperature



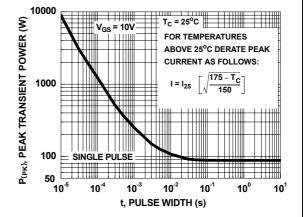


Figure 11. Forward Bias Safe Operating Area

Figure 12. Single Pulse Maximum Power Dissipation

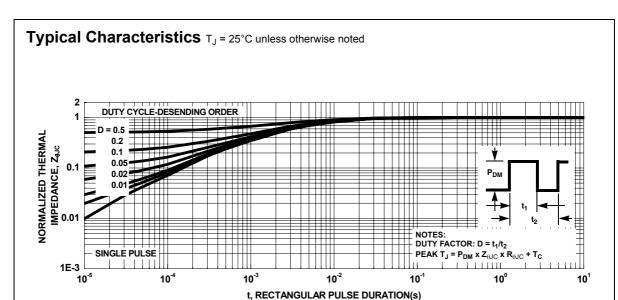


Figure 13. Transient Thermal Response Curve

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